

# Making Complex Protection and Control Systems Easy to Maintain

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# What Does This Mean?

Using a technology solution to address business needs

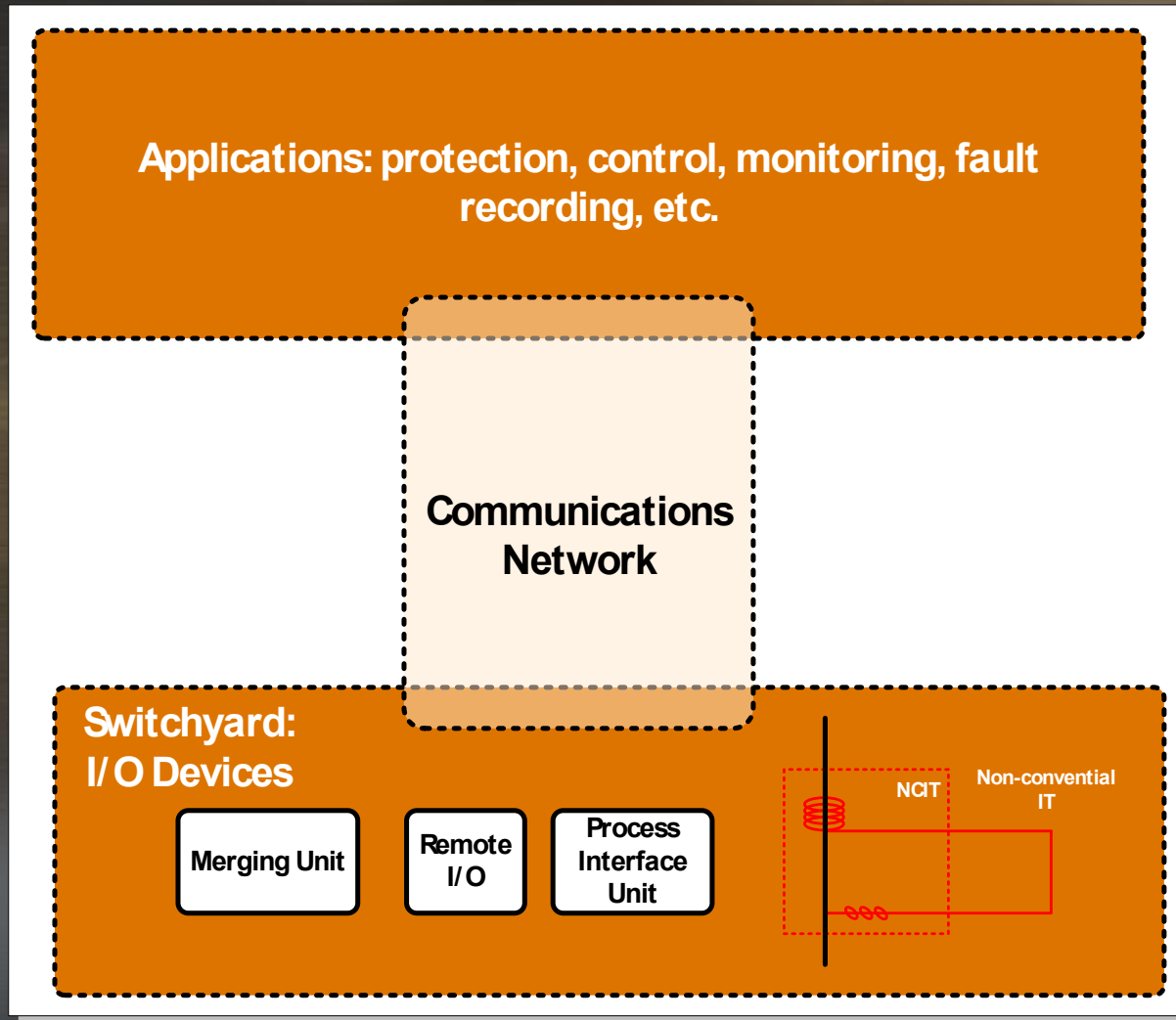
## Business need

- Cost and effort to maintain protection and control systems

## Technology solution

- Process bus

# Process Bus



# Process Bus Discussions To Date

## Business case

- Project cost advantages unclear
- Less skilled resources is a strong case for adoption

## Technical Issues

- Practical considerations for installation
- Network performance / concerns
- How to test
- Reducing the need for testing

## Reliability

- Availability will be the same as conventional

# The Big Questions

## Long term system reliability

- More parts make up a system
- Will process bus be as reliable

## Long term costs

- More parts make up a system
- What is the cost to maintain, with more possible device failures

# To Answer These Questions:

Process bus is a possible solution

If the end result is that



PDT (Process Down Time)  $\rightarrow 0$

Which only works if



MTTR (Mean Time to Repair or Replace)  $\rightarrow 0$

Devices can be quickly swapped out

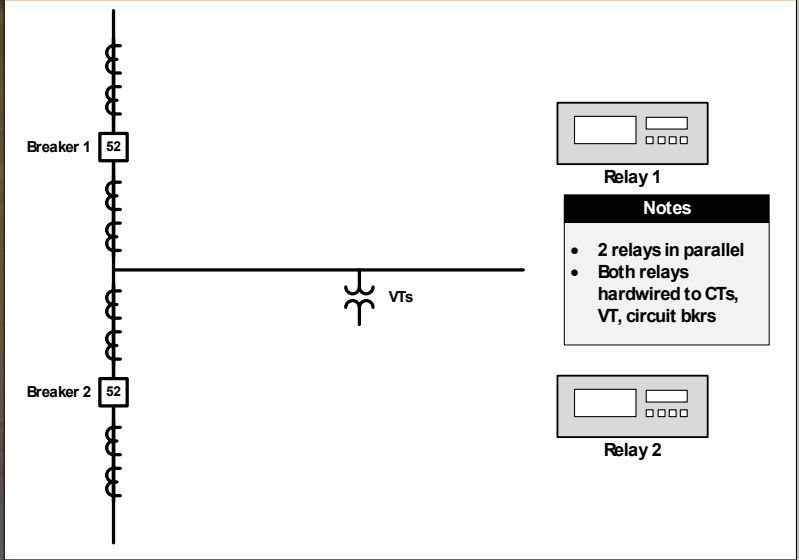
# Reliability Analysis



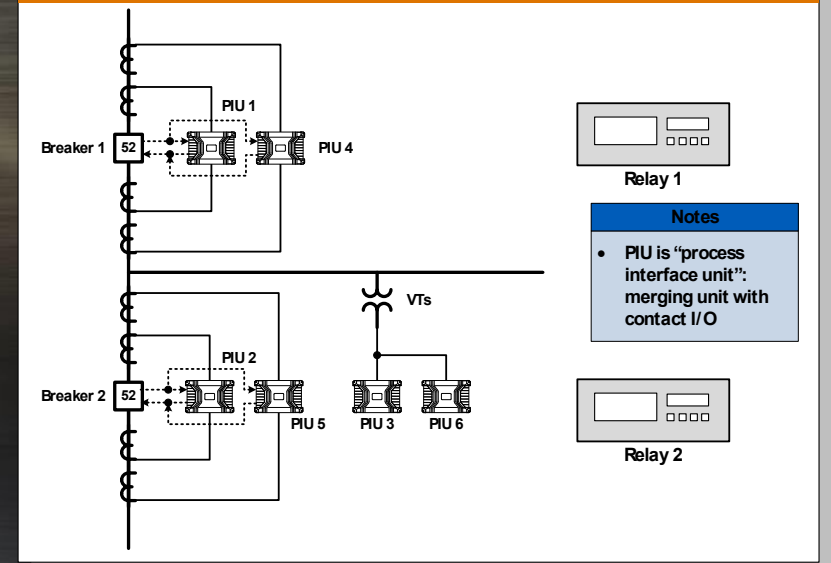
# Case Study

## *Breaker-and-a-half line terminal with process bus*

Case Study: Breaker-and-a-half Line Terminal



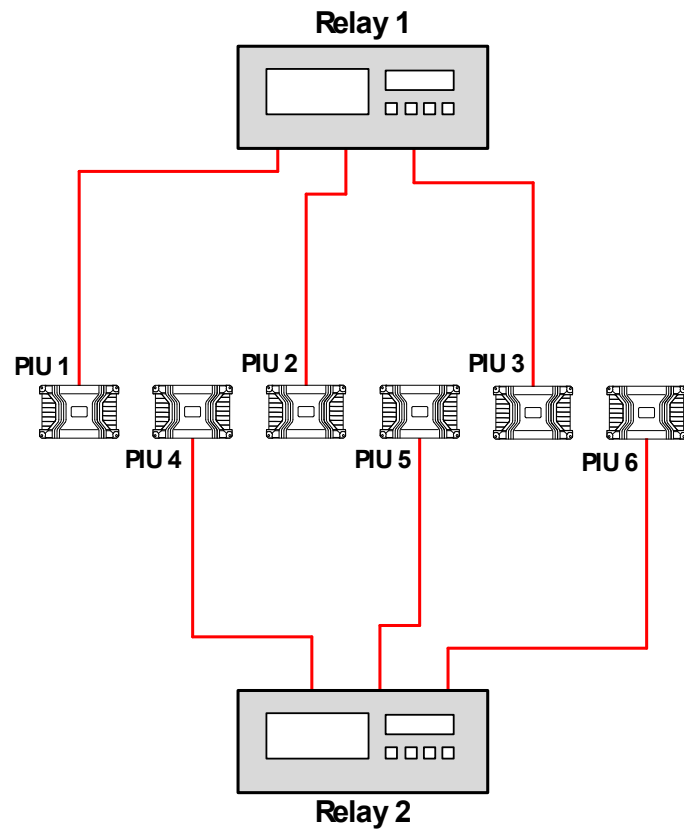
Process Bus Devices



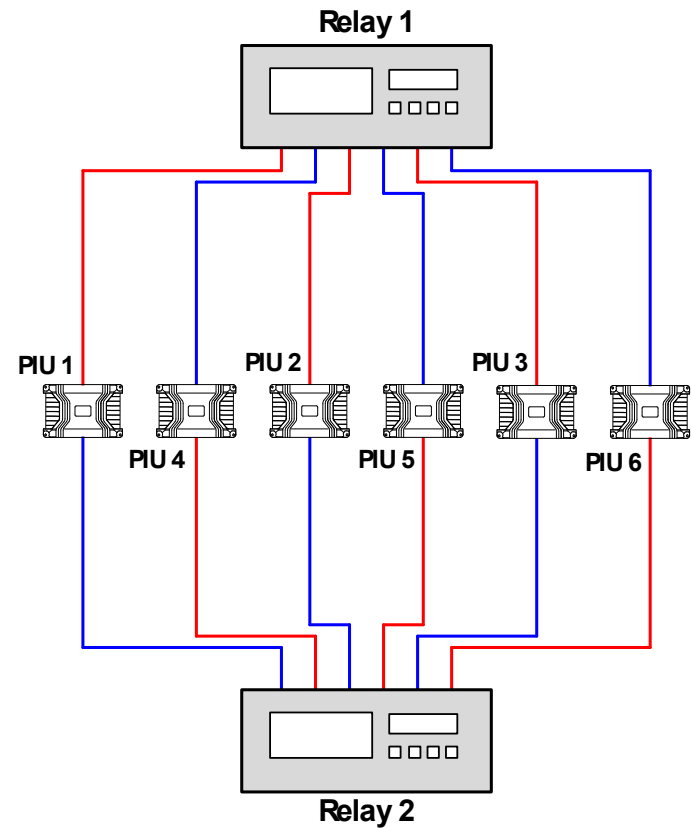


# Architectures

Architecture 1: Independent Point-to-Point Process Bus



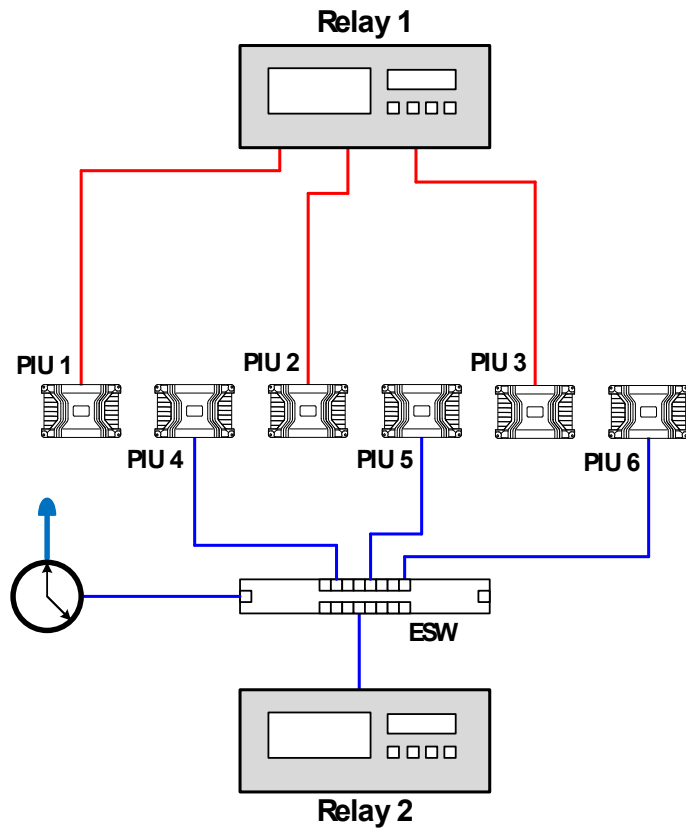
Architecture 2: Interoperable Point-to-Point Process Bus



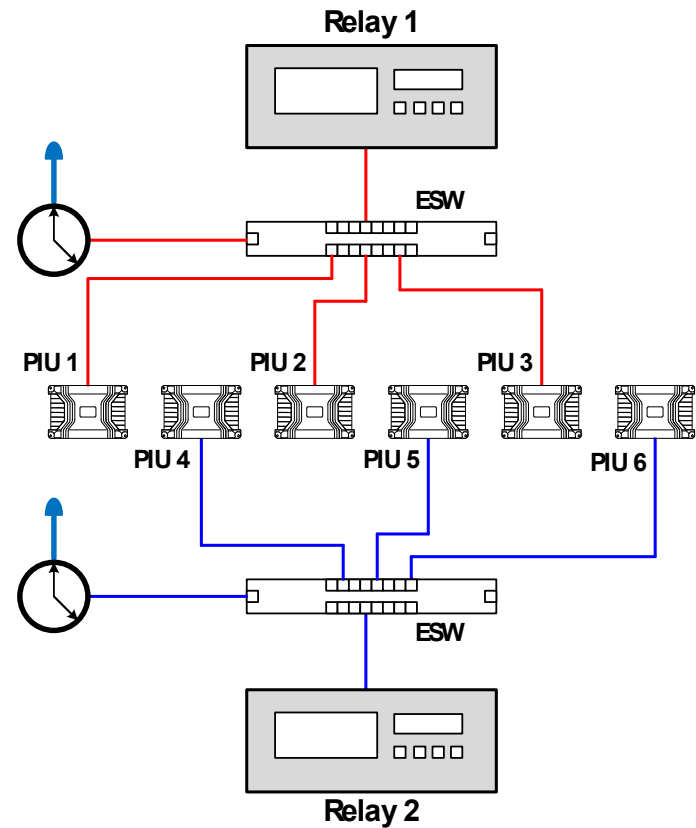
# Architectures

- continued

Architecture 3: Point-to-Point / Network Process Bus

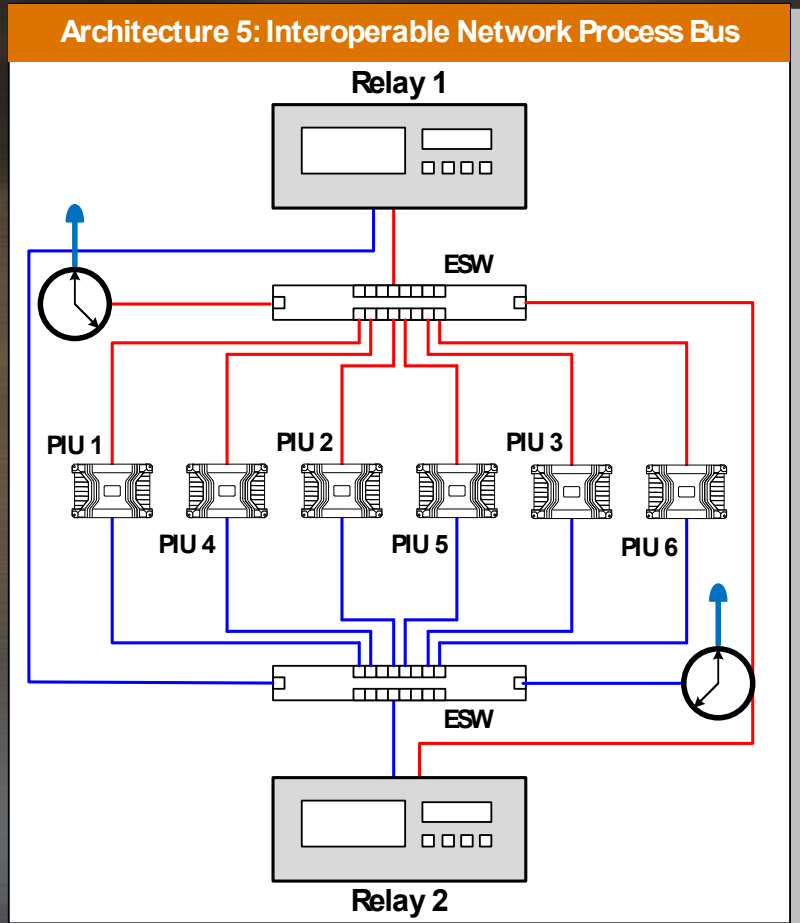


Architecture 4: Independent Network Process Bus



# Architectures

- continued



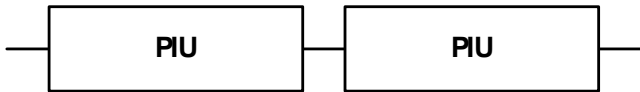
- All architectures are legitimate
- All have advantages / disadvantages in terms of cost, performance, reliability, usability
- Fault tree analysis shows any of these architectures will be as available as conventional protection

# Reliability Analysis

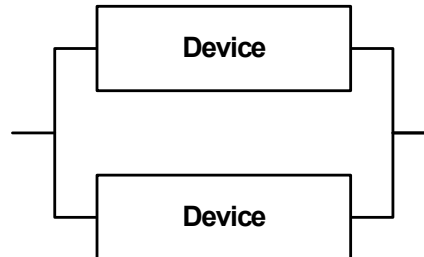
Reliability is defined by  $R(t) = e^{-\lambda t}$  where  $\lambda = \frac{1}{MTTF}$

## Reliability in concept (identical devices)

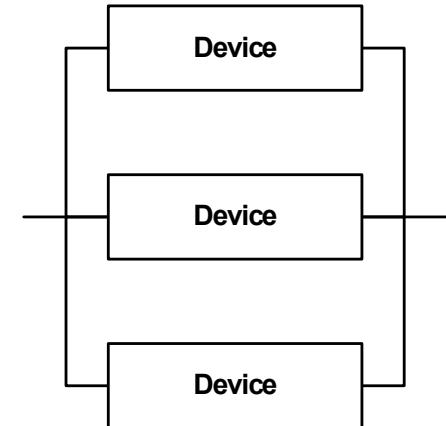
MTBF =  $\frac{1}{2}$  MTBF of individual device



MTBF = 1.5 x MTBF of individual device



MTBF = 1.83 x MTBF of individual device



# System Reliability Analysis

*Actual device data*

	General		At 1 year		At 10 years		At 20 years		At 30 years	
	Availability	MTBF	Reliability	Prob of Failure	Reliability	Prob of Failure	Reliability	Prob of Failure	Reliability	Prob of Failure
<b>Conv.</b>	1.00000	300	0.99998	0.0%	0.99762	0.2%	0.99094	0.9%	0.98060	1.9%
<b>Option 1</b>	1.00000	47	0.99903	0.1%	0.92659	7.3%	0.78053	21.9%	0.62486	37.5%
<b>Option 2</b>	1.00000	47	0.99974	0.0%	0.97646	2.4%	0.91522	8.5%	0.82995	17.0%
<b>Option 3</b>	1.00000	33	0.99586	0.4%	0.79411	20.6%	0.55853	44.1%	0.39599	60.4%
<b>Option 4</b>	1.00000	11	0.98232	1.8%	0.42253	57.7%	0.11196	88.8%	0.02749	97.3%
<b>Option 5</b>	1.00000	11	0.99183	0.8%	0.60797	39.2%	0.24339	75.7%	0.08357	91.6%

- Ethernet switches, clocks, clock antennas are the weak links

# System Reliability Analysis

*Ideal device data*

	General		At 1 year		At 10 years		At 20 years		At 30 years	
	Availability	MTBF	Reliability	Prob of Failure	Reliability	Prob of Failure	Reliability	Prob of Failure	Reliability	Prob of Failure
<b>Conv.</b>	1.00000	300	0.99998	0.0%	0.99762	0.2%	0.99094	0.9%	0.98060	1.9%
<b>Option 1</b>	1.00000	69	0.99954	0.0%	0.96226	3.8%	0.87695	12.3%	0.77256	22.7%
<b>Option 2</b>	1.00000	69	0.99988	0.0%	0.98899	1.1%	0.95873	4.1%	0.91349	8.7%
<b>Option 3</b>	1.00000	59	0.99933	0.1%	0.94680	5.3%	0.83418	16.6%	0.70570	29.4%
<b>Option 4</b>	1.00000	47	0.99901	0.1%	0.92501	7.5%	0.77655	22.3%	0.61918	38.1%
<b>Option 5</b>	1.00000	47	0.99983	0.0%	0.98391	1.6%	0.94010	6.0%	0.87573	12.4%

- Assumes all devices have an identical MTBF of 200 years.

# Comments on Reliability Analysis

## Simplistic modeling

- Assumes failed devices aren't replaced
- Assumes replacement devices have same reliability, are same age as failed devices

In practice, reliability will be better than this

## Obvious conclusions:

- Point-to-point is better than LAN (fewer devices in critical path)
- Redundant point-to-point is better (parallel paths)



# Practical Considerations For Reliability

## *System Design*

- Point-to-point: MTBF of 50 years, 95% reliability over 20 years
- Can we make LAN match this?
- Switches and clocks are the weak link
- Triple redundant networks, triple redundant clocks don't really improve MTBF, reliability
  - Clock ---> 11 years for 1, 17 years for 2, 20 years for 3
  - Not a practical solution anyway

# Practical Considerations For Reliability

## *Device Design*

- Make devices better
- To have a system MTBF of 50 years on LAN

$$MTBF = 50 = \frac{MTBF \text{ per device}}{6 \text{ devices}}$$

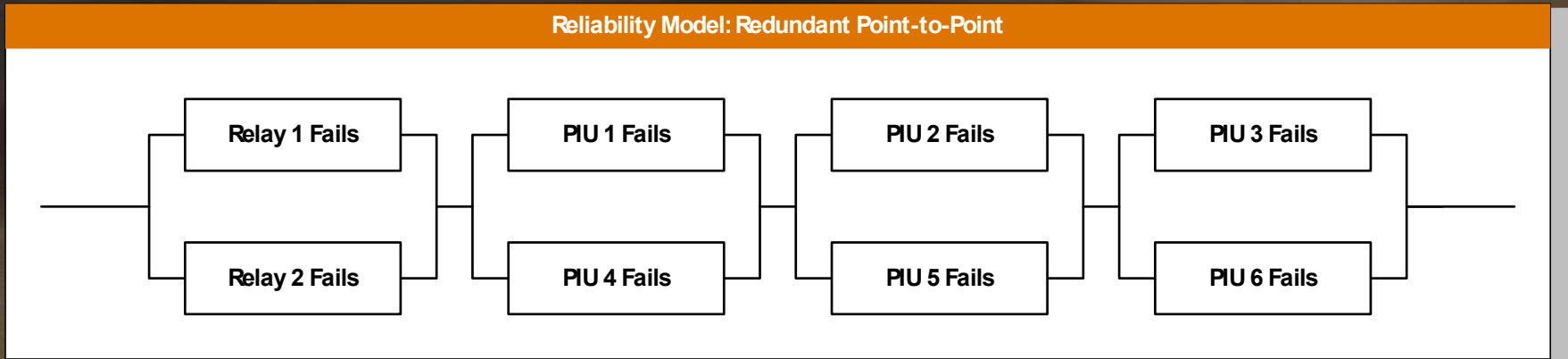
- Individual devices must have MTBF of 200 years
  - Relays there, possible for PIUs
  - Difficult for clocks (antennas, oscillators, transceivers)
  - Not really possible for switches (transceivers, power supplies). Already really optimized

# Practical Considerations For Reliability

## *Make Repair Better*

- Focus on MDT (Mean Down Time) or PDT (Process Down Time)
- PDT is total time down for problem diagnosis, device repair / replacement, testing
- Must focus on PDT for process bus
- Process bus PDT can (and should, and must) be lower than conventional PDT!

# Making Protection And Control Systems Easier To Maintain

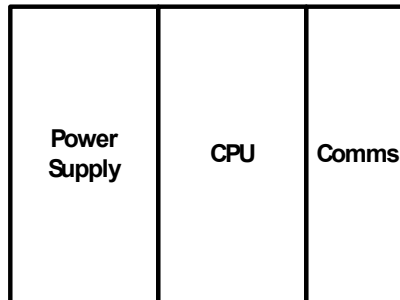


- System works with any individual device failure
- Treat devices as “black boxes”, or modules
  - Connectorized, defined functions
  - Simple swap out to replace failed unit
  - Don't test, don't analyze, just replace on alarms

# Reducing PDT

## Process Bus: Ideal Devices to Reduce PDT

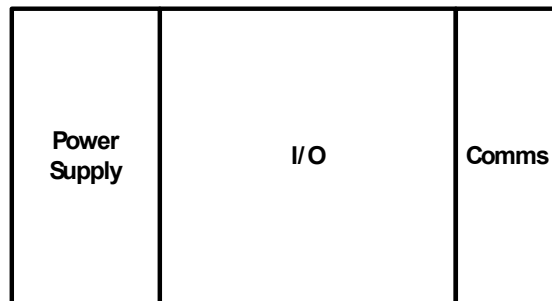
### Relay



Simple field replacement through  
“plug and play”

- | Relay   |
|---|
| <ul style="list-style-type: none"><li>• Plug in power supply for simple field replacement</li><li>• Plug in communications module for simple replacement</li><li>• Reduces PDT for most common failure components towards 0</li></ul> |

### PIU or I/O Device



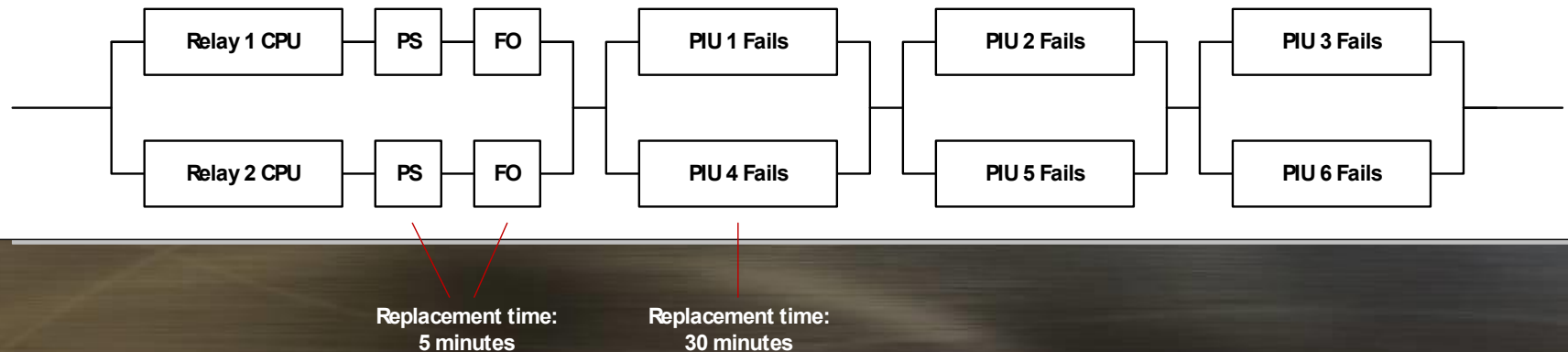
Connectorized field wiring  
Remove and replace entire unit without  
recommissioning

- | Distributed I/O  |
|--|
| <ul style="list-style-type: none"><li>• Connectorized field wiring to support simple physical replacement</li><li>• Settings free device to support only simple physical replacement</li><li>• No recommissioning necessary on replacement reduces PDT towards 0</li></ul> |



# Reducing PDT

Reliability Model: Redundant Point-to-Point, Designed for Replacement



- Power supply and transceivers are plug-in modules
- PIUs can be easily designed as modules
- Even Relay CPU / application replacement is simpler

# Conclusions

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- The real concern with protection and control systems is PDT
- PDT is better with process bus
- Repair process is swap out failed devices
- Can implement “run to failure” modes, regular replacement cycles
- Makes device failure and repair a known, predictable quantity



Thank You

Questions?